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- Each Device Drives Ten Lines
- 60-V Output Voltage Rating
- 40-mA Output Source Current
- High-Speed Serially-Shifted Data Input
- CMOS-Compatible Inputs
- Latches on All Driver Outputs
- Improved Direct Replacement for UCN4810A and TL4810A

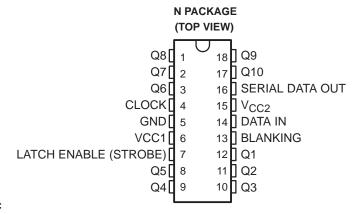
#### description

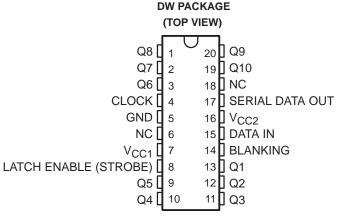
The TL4810B and TL4810BI are monolithic BIDFET† integrated circuits designed to drive a dot matrix or segmented vacuum fluorescent display (VFD). These devices feature a serial data output to cascade additional devices for large display arrays.

A 10-bit data word is serially loaded into the shift register on the positive-going transitions of the clock. Parallel data is transferred to the output buffers through a 10-bit D-type latch while LATCH ENABLE is high and is latched when LATCH ENABLE is low. When BLANKING is high, all outputs are low.

Outputs are totem-pole structures formed by npn emitter-follower and double-diffused MOS (DMOS) transistors with output voltage ratings of 70 V and 40-mA source-current capability. All inputs are compatible with CMOS and TTL levels, but each requires the addition of a pullup resistor to  $V_{CC1}$  when driven by TTL logic.

The TL4810B is characterized for operation from 0°C to 70°C. The TL4810BI is characterized for operation from –40°C to 85°C.





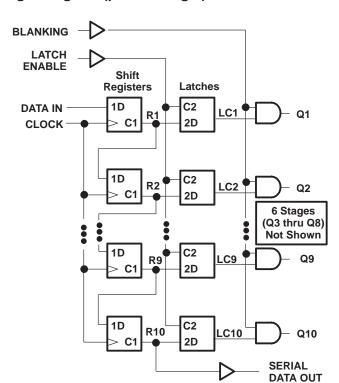
NC-No internal connection

†BIDFET - Bipolar, double-diffused, N-channel and P-channel MOS transistors on same chip. This is a patented process.

#### logic symbol<sup>†</sup>

#### CMOS/VAC **FLUOR DISP** LATCH 7 **ENABLE** BLANKING 13 EN<sub>3</sub> **SRG10** CLOCK C1/→ 12 Q1 DATA IN $\frac{14}{}$ 1D 2D $\triangleright$ 3 11 Q2 2D $\triangleright$ 3 10 2D $\triangleright$ 3 Q3 9 Q4 2D $\triangleright$ 3 8 Q5 2D $\triangleright$ 3 3 Q6 2D $\triangleright$ 3 2 Q7 2D $\triangleright$ 3 1 2D $\triangleright$ 3 Q8 18 Q9 2D $\triangleright$ 3 17 Q10 2D $\triangleright$ 3 16 SERIAL **DATA OUT**

logic diagram (positive logic)



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the N package.

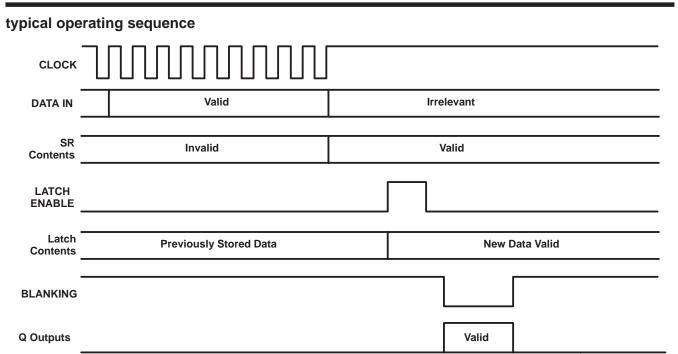
#### **FUNCTION TABLE**

	CONTROL INPUTS			SHIFT REGISTERS	LATCHES		OUTPUTS			
FUNCTION	CLOCK	LATCH ENABLE	BLANKING	R1 THRU R10‡	LC1 THRU LC10	SERIAL	Q1 THRU Q10			
Load	↑ No↑	X X	X X	Load and shift <sup>‡</sup> No change	Determined by LATCH ENABLE§	R10	Determined by BLANKING			
Latch	X X	L H	X X	As determined above	Stored data New data	R10	Determined by BLANKING			
Blank	X	X	H L	As determined above	Determined by LATCH ENABLE§	R10	All L LC1 thru LC10, respectively			

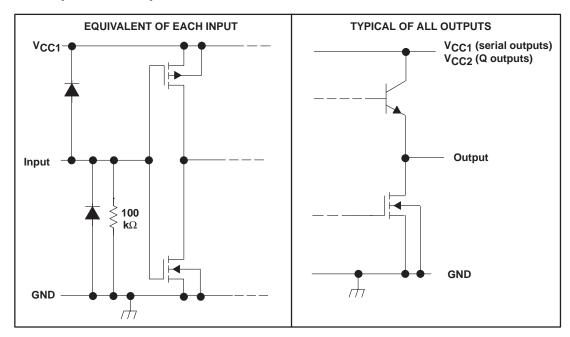
H = high level, L = low level, X = irrelevant,  $\uparrow = low-to-high-level transition$ .

<sup>‡</sup>Register R10 takes on the state of R9, R9 takes on the state of R8...R2 takes on the state of R1, and R1 takes on the state of the data input.

<sup>§</sup> New data enter the latches while LATCH ENABLE is high. These data are stored while LATCH ENABLE is low.



#### schematics of inputs and outputs



# TL4810B, TL4810BI VACUUM FLUORESCENT DISPLAY DRIVERS

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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Logic supply voltage, V <sub>CC1</sub> (see Note 1)	18 V
Driver supply voltage, V <sub>CC20</sub>	70 V
Output voltage, VO	70 V
Input voltage range, V <sub>I</sub>	$-0.3 \text{ V}$ to $V_{CC1} + 0.3 \text{ V}$
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub> : TL4810B	0°C to 70°C
TL4810BI	–40°C to 85°C
Storage temperature range, T <sub>stq</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

NOTE 1: Voltage values are with respect to GND.

#### DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING
DW	1125 mW	9.0 mW/°C	720 mW	585 mW
N	1150 mW	9.2 mW/°C	736 mW	598 mW

#### recommended operating conditions

PARAMETER			TL4810B		TL4810BI		
			MAX	MIN	MAX	UNIT	
Supply voltage, V <sub>CC1</sub>		4.75	15.75	4.75	15.75	V	
Supply voltage, V <sub>CC2</sub>	5	60	5	60	V		
High lovel input voltage Vv.	V <sub>CC1</sub> = 5 V	3.5	5.3	3.5	5.3	V	
High-level input voltage, VIH	V <sub>CC1</sub> = 15 V	13.5	15.3	13.5	15.3	V	
Low-level input voltage, V <sub>IL</sub>	-0.3†	0.8	-0.3†	0.8	V		
Continuous high-level output curr		-25		-25	mA		
Operating free-air temperature, T	A .	0	70	-40	85	°C	

<sup>†</sup> The algebraic convention, in which the less positive (more negative) limit is designated as minimum, is used in this data sheet for logic voltages only.



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## electrical characteristics over recommended operating free-air temperature range, $V_{CC1} = 5 \text{ V}$ to 15 V, $V_{CC2} = 60 \text{ V}$ , GND = 0 (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		TL4810B			TL4810BI			UNIT	
	PARAMETE	K	TEST CONDITIONS:		MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	ONIT
	High-level	Q outputs	I <sub>OH</sub> = -25 mA		57.5	58		57.5	58		
VOH	output	SERIAL	V <sub>CC1</sub> = 5 V,	$I_{OH} = -100  \mu A$	4	4.5		4	4.5		V
	voltage	DATA OUT	V <sub>CC1</sub> = 15 V,	$I_{OH} = -100  \mu A$	14	14.7		14	14.7		
	Low-level	Q outputs	$I_{OL} = 1 \mu A$ ,	BLANKING at V <sub>CC1</sub>		0.5	1		0.5	1	
VOL	output	SERIAL	V <sub>CC1</sub> = 5 V,	I <sub>OL</sub> = 100 μA		0.05	0.1		0.05	0.1	V
	voltage	DATA OUT	V <sub>CC1</sub> = 15 V,	I <sub>OL</sub> = 100 μA		0.02	0.1		0.02	0.1	
	Low-level Q output current (pulldown current)		$V_O = 60 \text{ V},$ $T_A = \text{MIN to } 70^{\circ}\text{C}$	BLANKING at V <sub>CC1</sub> ,	2.5	3.7		2.5	3.7		· mA
lOL			V <sub>O</sub> = 60 V, T <sub>A</sub> = 85°C	BLANKING at V <sub>CC1</sub> ,				2			
I <sub>O(off)</sub>	Off-state output current		$V_O = 0,$ $T_A = MAX$	BLANKING at V <sub>CC1</sub> ,		-1	-15		-1	-15	μΑ
lΗ	High-level input current		$V_I = V_{CC1}$			30	50		30	50	μΑ
			All inputs at 0 V,	V <sub>CC1</sub> = 5 V		10	50		10	50	
loor	Supply current from V <sub>CC1</sub>		One Q output high	V <sub>CC1</sub> = 15 V		10	100		10	100	^
ICC1	Supply current	IIOIII VCC1	All inputs at 0 V,	V <sub>CC1</sub> = 5 V		10	50		10	50	μΑ
			All outputs low	V <sub>CC1</sub> = 15 V		10	100		10	100	
			All outputs low			0.5	1		0.5	1	
I <sub>CC2</sub>	Supply current	from V <sub>CC2</sub>	All outputs high,	$T_A = 0$ °C to MAX		2.7	4		2.7	4	mA
			All outputs high,	T <sub>A</sub> = -40°C		_				5	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

#### timing requirements over recommended operating free-air temperature range

		V <sub>CC1</sub> = 5 V		V <sub>CC1</sub> =	UNIT	
		MIN	MAX	MIN	MAX	UNIT
tw(CKH)	Pulse duration, CLOCK high	250		50		ns
tw(LEH)	Pulse duration, LATCH ENABLE high	250		50		ns
t <sub>su(D)</sub>	Setup time, DATA IN before CLOCK↑	125		25		ns
t <sub>h(D)</sub>	Hold time, DATA IN after CLOCK↑	125		25		ns
<sup>t</sup> d(CKH-LEH)	Delay time, CLOCK↑ to LATCH ENABLE high	125		25		ns

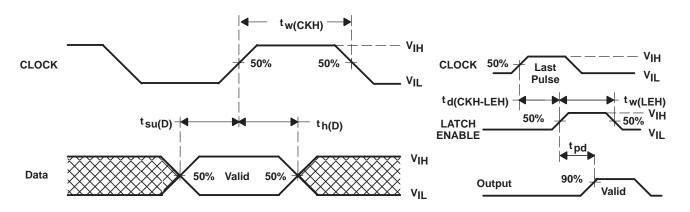
### switching characteristics, $V_{BB}$ = 60 V, $T_A$ = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
	Propagation delay time I ATCH ENABLE to O outputs	V <sub>CC1</sub> = 5 V		1			
<sup>t</sup> pd	Propagation delay time, LATCH ENABLE to Q outputs	V <sub>CC1</sub> = 15 V		0.5		μs	



<sup>&</sup>lt;sup>‡</sup> All typical values are at  $T_A = 25$ °C, except for  $I_O$ .

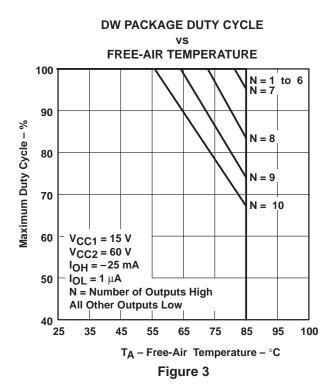
#### PARAMETER MEASUREMENT INFORMATION

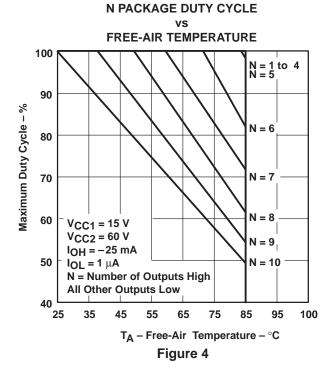


**Figure 1. Input Timing** 

**Figure 2. Output Switching Times** 

#### THERMAL INFORMATION





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